

## 1.Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low  $R_{DS(ON)}$  and fast switching speed.

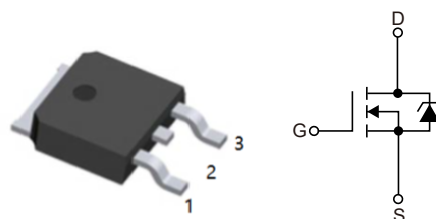
## 2.Features

- $V_{DS(V)}=30V$
- $R_{DS(ON)}<9m\Omega(V_{GS}=10V)$
- $R_{DS(ON)}<12m\Omega(V_{GS}=4.5V)$
- Low gate resistance
- High power and current handling capability
- High performance trench technology for extremely low  $R_{DS(ON)}$

## 3.Pinning information

Pin	Symbol	Description
1	G	GATE
2	D	DRAIN
3	S	SOURCE

TO-252(DPAK)  
top view



## 4.Absolute Maximum Ratings $T_c=25^{\circ}C$

Parameter	Symbol	Rating	Units
Drain to Source Voltage	$V_{DSS}$	30	V
Gate to Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current Continuous ( $T_c=25^{\circ}C$ , $V_{GS}=10V$ ) (Note 1)	$I_D$	58	A
Continuous ( $T_c=25^{\circ}C$ , $V_{GS}=4.5V$ ) (Note 1)		51	A
Continuous ( $T_{amb}=25^{\circ}C$ , $V_{GS}=10V$ , with $R_{\theta JA}=52^{\circ}C/W$ )		13	A
Pulsed		Figure 4	A
Single Pulse Avalanche Energy (Note 2)	$E_{AS}$	53	mJ
Power Dissipation	$P_D$	55	W
Derate above $25^{\circ}C$		0.37	$^{\circ}C/W$
Storage Temperature	$T_J, T_{STG}$	-55 to 175	$^{\circ}C$



5.Thermal Characteristics

Parameter	Symbol	Rating	Units
Thermal Resistance, Junction-to-Case TO-252,TO-251	$R_{\theta JC}$	2.73	°C/W
Thermal Resistance, Junction-to-Ambient TO-252,TO-251	$R_{\theta JA}$	100	°C/W
Thermal Resistance, Junction-to-Ambient TO-252,1in <sup>2</sup> copper pad area	$R_{\theta JA}$	52	°C/W



## 6. Electrical Characteristic (T<sub>c</sub>=25°C unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units	
Off Characteristics							
Drain to Source Breakdown Voltage	BV <sub>DSS</sub>	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V	30			V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =24V			1	μA	
Gate to Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V			±100	nA	
On Characteristics							
Gate to Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	1.2		2.5	V	
Drain to Source On Resistance	R <sub>DS(ON)</sub>	I <sub>D</sub> =35A, V <sub>GS</sub> =10V		7	9	mΩ	
		I <sub>D</sub> =35A, V <sub>GS</sub> =4.5V		9	12	mΩ	
Dynamic Characteristics							
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =15V, V <sub>GS</sub> =0V, f=1MHz		1260		pF	
Output Capacitance	C <sub>oss</sub>			260		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>			150		pF	
Gate Resistance	R <sub>g</sub>	V <sub>GS</sub> =0.5V, f=1MHz		2.3		Ω	
Total Gate Charge at 10V	Q <sub>g(TOT)</sub>	V <sub>GS</sub> =0V to 10V	V <sub>DD</sub> =15V	23	31	nC	
Total Gate Charge at 5V	Q <sub>g(5)</sub>	V <sub>GS</sub> =0V to 5V		I <sub>D</sub> =35A	13	17	nC
Threshold Gate Charge	Q <sub>g(TH)</sub>	V <sub>GS</sub> =0V to 1V		I <sub>g</sub> =1mA	1.3	1.7	nC
Gate to Source Gate Charge	Q <sub>gs</sub>			3.8		nC	
Gate Charge Threshold to Plateau	Q <sub>gs2</sub>			2.5		nC	
Gate to Drain “Miller” Charge	Q <sub>gd</sub>			5		nC	
Turn-On Time	t <sub>(on)</sub>	V <sub>DD</sub> =15V, I <sub>D</sub> =35A			147	ns	
Turn-On Delay Time	t <sub>D(on)</sub>			8		ns	
Rise Time	t <sub>r</sub>			91		ns	
Turn-Off DelayTime	t <sub>D(off)</sub>		V <sub>GS</sub> =10V, R <sub>GS</sub> =10Ω		38	ns	
Fall Time	t <sub>f</sub>				32		ns
Turn-Off Time	t <sub>off</sub>					108	ns



Drain–Source Diode Characteristics						
Source to Drain Diode Forward Voltage	$V_{SD}$	$I_{SD}=35A$			1.25	V
		$I_{SD}=15A$			1	V
Reverse Recovery Time	$t_{rr}$	$I_F=35A, di/dt=100A/\mu s$			27	ns
Reverse Recovery Charge	$Q_{rr}$	$I_F=35A, di/dt=100A/\mu s$			14	nC

Notes:

1: Package current limitation is 35A.



## 7.1 Typical characteristic

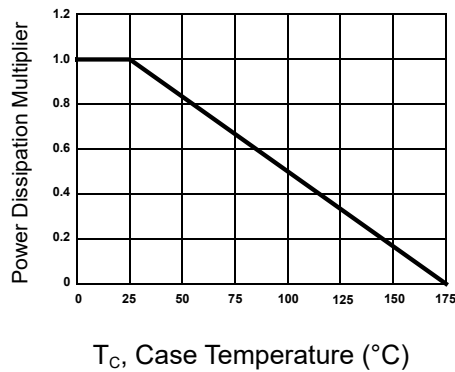


Figure 1: Normalized Power Dissipation vs Case Temperature

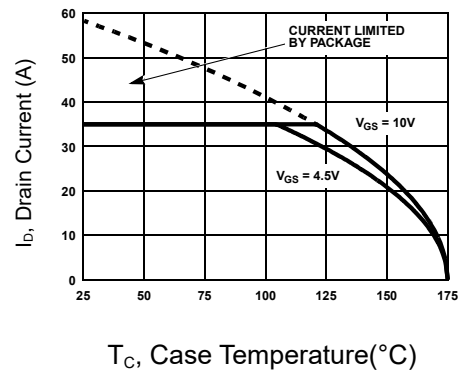


Figure 2: Maximum Continuous Drain Current vs Case Temperature

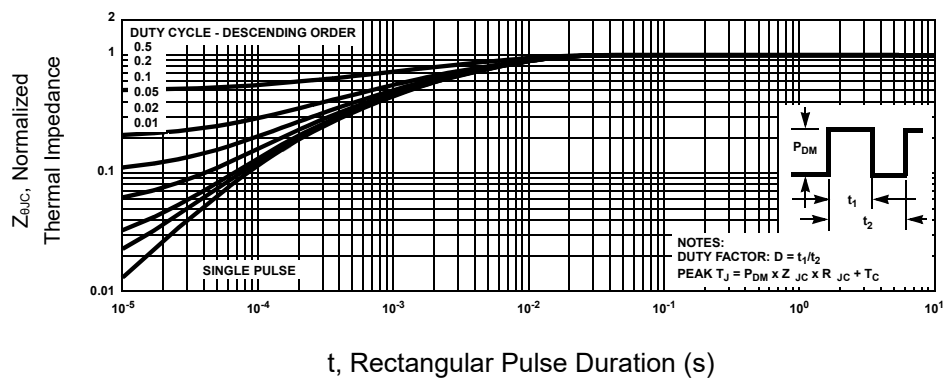


Figure 3: Normalized Maximum Transient Thermal Impedance

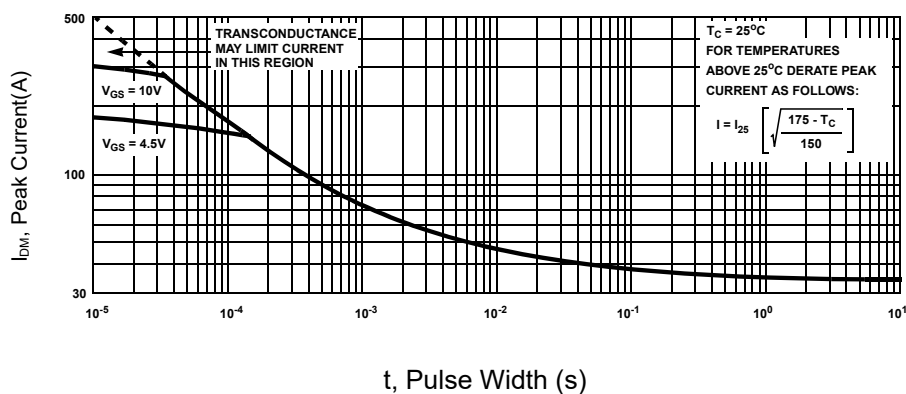


Figure 4: Peak Current Capability



## 7.2 Typical characteristic

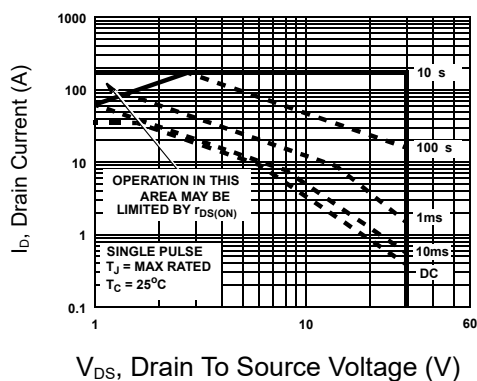


Figure 5: Forward Bias Safe Operating Area

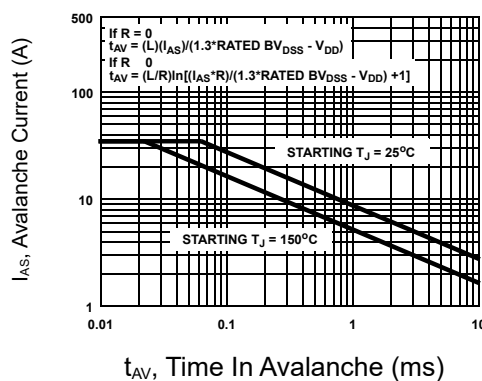


Figure 6: Unclamped Inductive Switching Capability

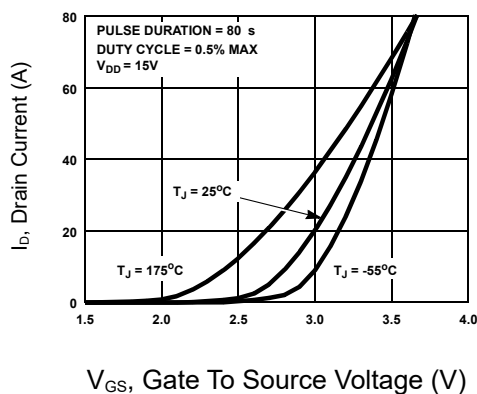


Figure 7: Transfer Characteristics

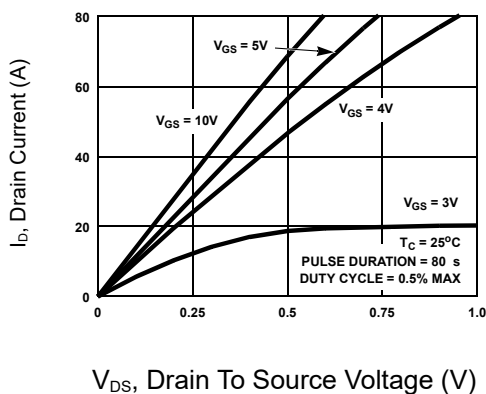


Figure 8: Saturation Characteristics

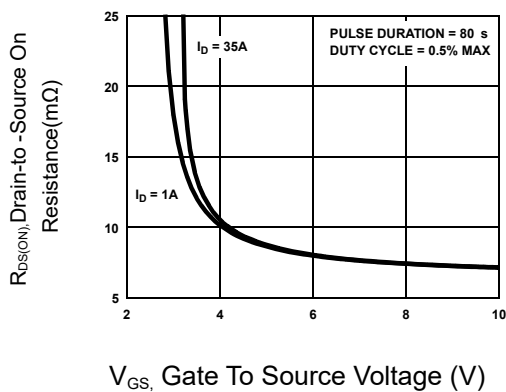


Figure 9: Drain to Source On Resistance vs Gate Voltage and Drain Current

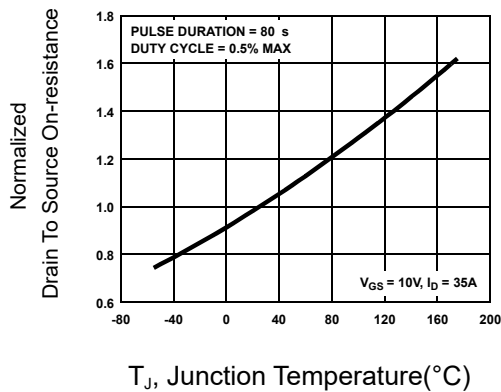
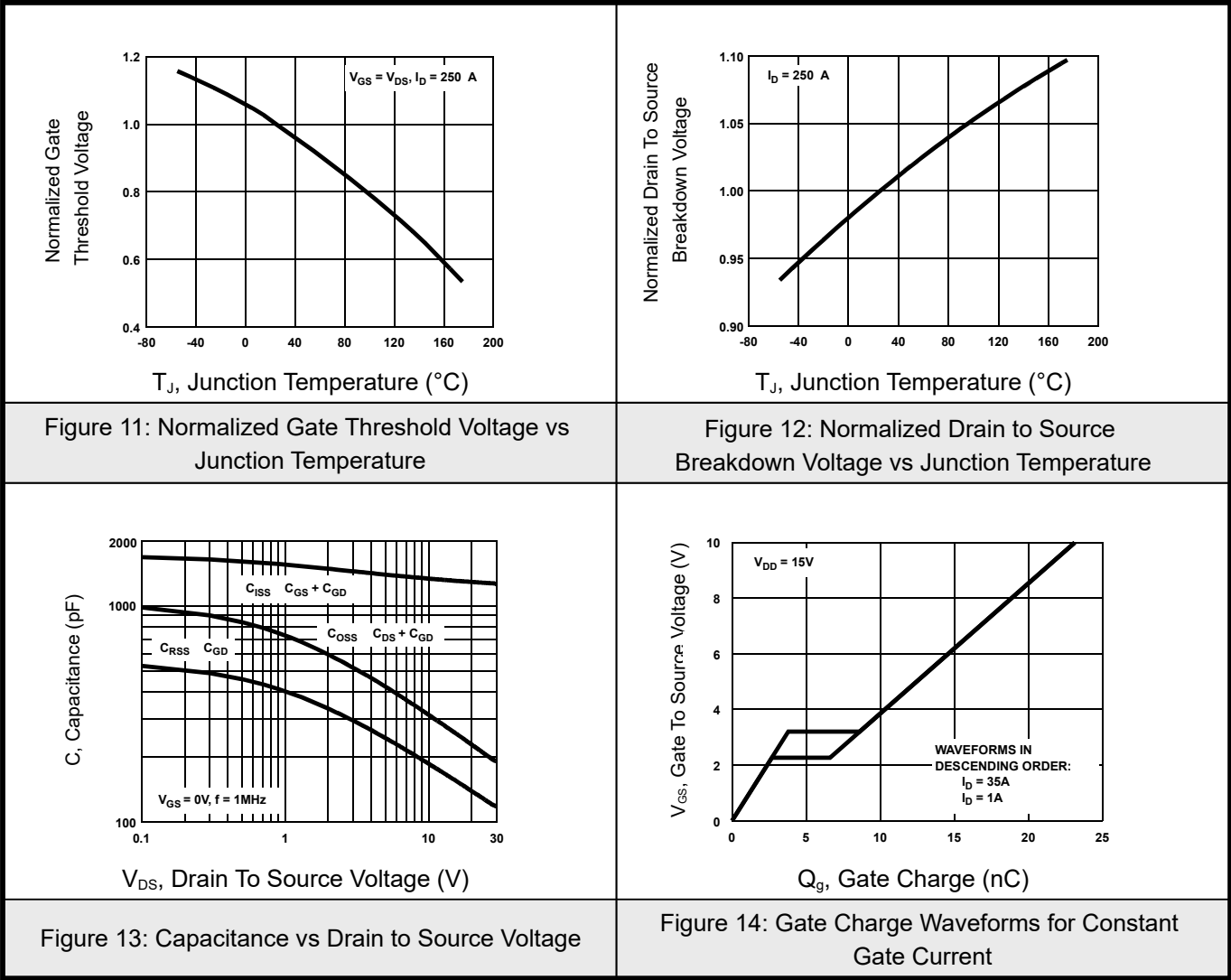


Figure 10: Normalized Drain to Source On Resistance vs Junction Temperature



7.3Typical characteristic





## 7.4 Typical characteristic

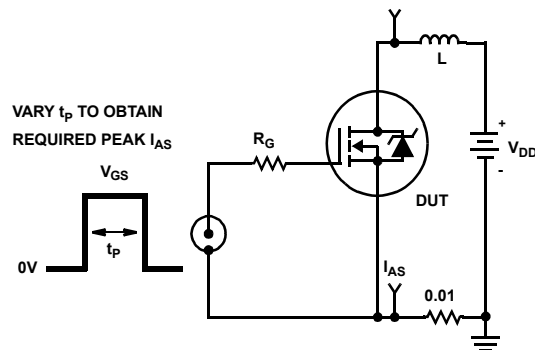


Figure 15. Unclamped Energy Test Circuit

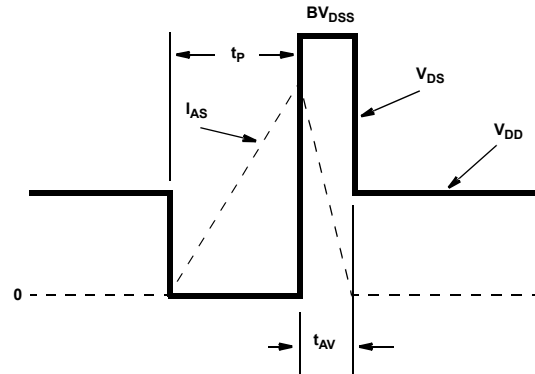


Figure 16. Unclamped Energy Waveforms

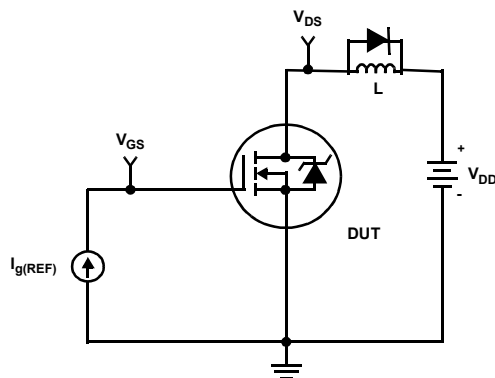


Figure 17. Gate Charge Test Circuit

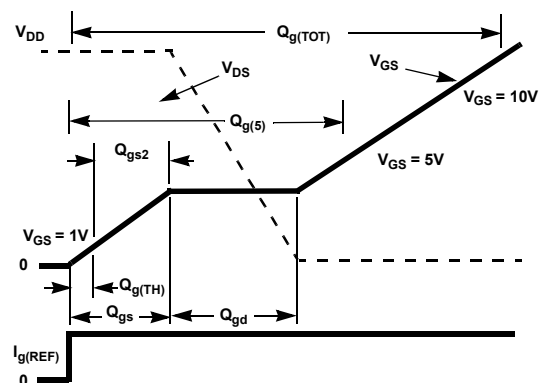


Figure 18. Gate Charge Waveforms

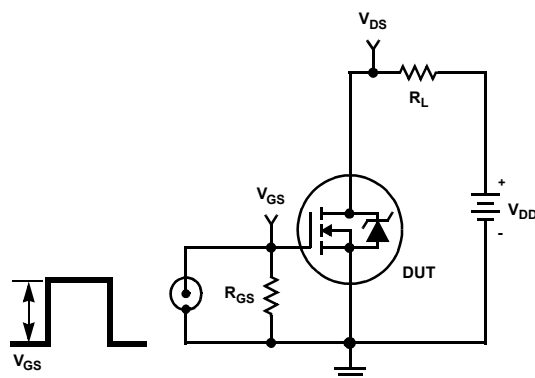


Figure 19. Switching Time Test Circuit

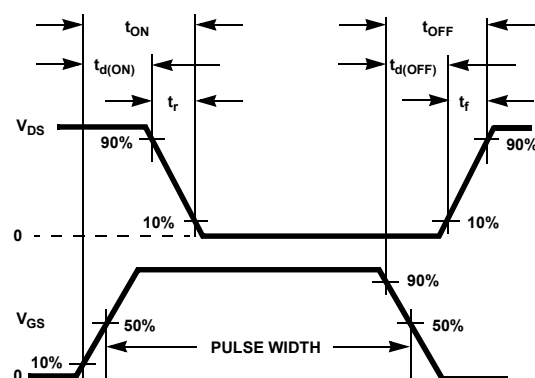
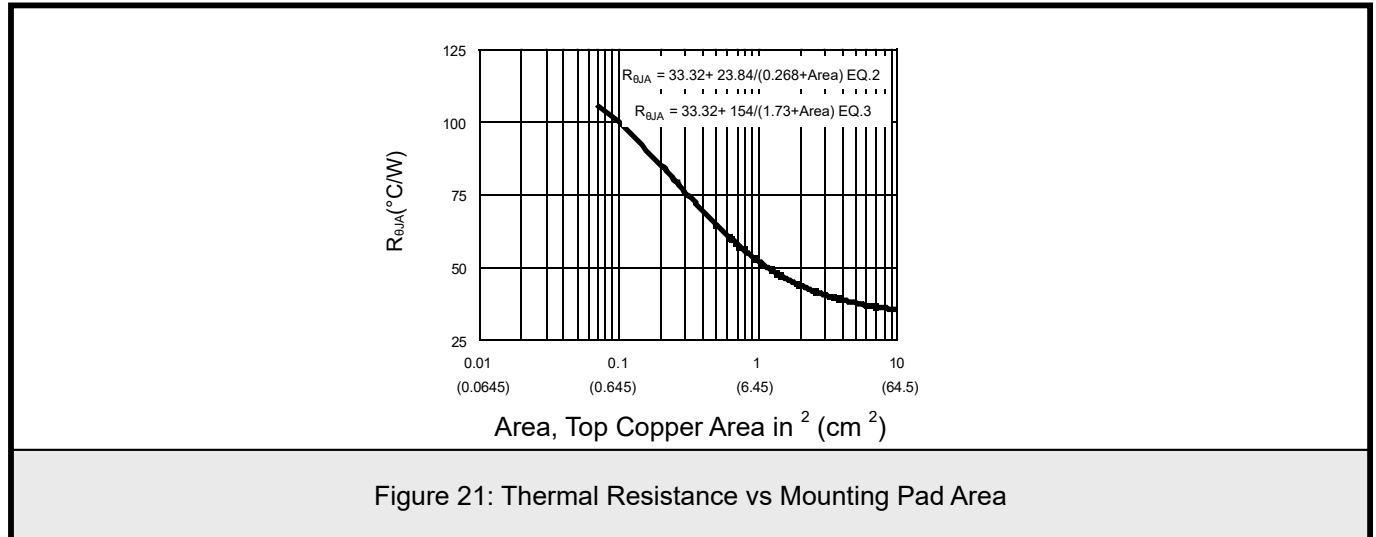


Figure 20. Switching Time Waveforms





## 7.5 Typical characteristic



### Notes:

The maximum rated junction temperature,  $T_{JM}$ , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation,  $P_{DM}$ , in an application. Therefore the application's ambient temperature,  $T_A(^{\circ}C)$ , and thermal resistance  $R_{\theta JA}(^{\circ}C/W)$  must be reviewed to ensure that  $T_{JM}$  is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}} \quad (\text{EQ. 1})$$

In using surface mount devices such as the TO-252 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of PDM is complex and influenced by many factors:

1. Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
2. The number of copper layers and the thickness of the board.
3. The use of external heat sinks.
4. The use of thermal vias.
5. Air flow and board orientation.
6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.



Figure 21 defines the  $R_{\theta JA}$  for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\theta JA} = 33.32 + \frac{23.84}{(0.268 + \text{Area})} \quad (\text{EQ. 2})$$

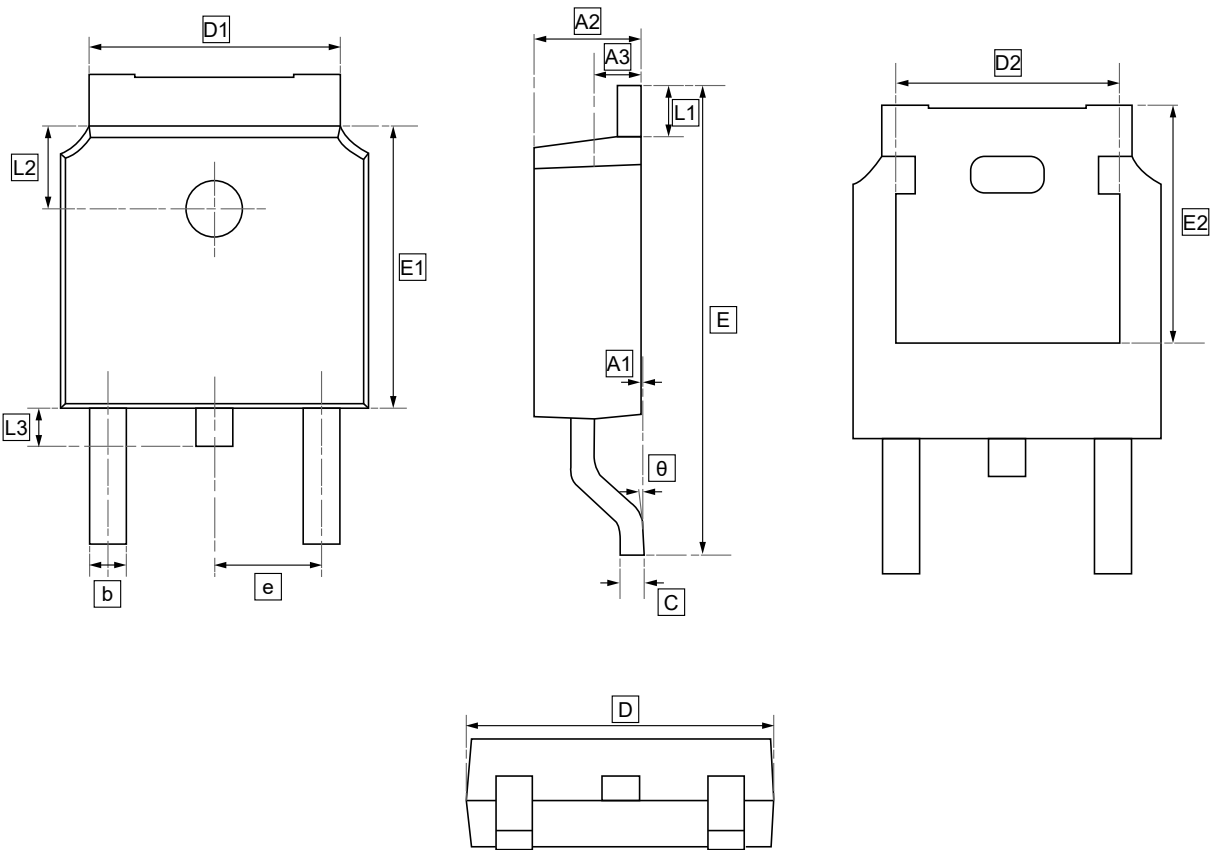
Area in Inches Squared

$$R_{\theta JA} = 33.32 + \frac{154}{(1.73 + \text{Area})} \quad (\text{EQ. 3})$$

Area in Centimeters Squared



8.TO-252 Package Outline Dimensions

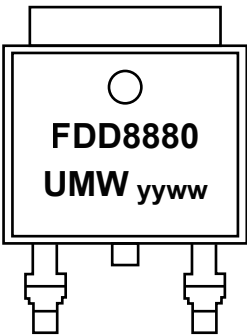


DIMENSIONS (mm are the original dimensions)

Symbol	A1	A2	A3	b	c	D	D1	D2	E	E1	E2	e	L1	L2	L3	θ
Min	0.00	2.18	0.90	0.65	0.46	6.35	4.95	4.32	9.40	5.97	5.21	2.286	0.89	1.70	0.60	0.00
Max	0.13	2.39	1.10	0.85	0.61	6.73	5.46	4.90	10.41	6.22	5.38		1.27	1.90	1.00	8.00



9.Ordering information



yy: Year Code  
ww: Week Code

Order Code	Package	Base QTY	Delivery Mode
UMW FDD8880	TO-252	2500	Tape and reel



## 10.Disclaimer

UMW reserves the right to make changes to all products, specifications. Customers should obtain the latest version of product documentation and verify the completeness and currency of the information before placing an order.

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